



IFW
PATENT
Docket No.: 11809/27

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

APPLICANTS : Glen CAREY, et al.
SERIAL NO. : 10/735,695
FILED : 16 December 2003
FOR : METHOD OF FABRICATION OF A SUPPORT
STRUCTURE FOR SEMICONDUCTOR
DEVICE
GROUP ART UNIT : 2812
EXAMINER :
COMMISSIONER FOR PATENTS
P. O. Box 1450
Alexandria, Virginia 22313-1450

INFORMATION DISCLOSURE STATEMENT
UNDER 37 C.F.R. § 1.97 & § 1.98

SIR:

In conformance with Applicants' duty of disclosure under 37 C.F.R. § 1.56 and § 1.97(b)(3), the references listed on the attached form PTO-1449 are hereby brought to the Examiner's attention.

In accordance with the requirements of 37 C.F.R. § 1.98, copies of the references are submitted herewith.

The references were cited in the International Search Report of the corresponding International Application No. PCT/US03/39876. A copy of the Search Report is enclosed.

It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the references be made of record therein and appear in the "references cited" on any patent to issue therefrom.

Respectfully submitted,



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Date: 28 June 2004

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FORM PTO-1449

INFORMATION DISCLOSURE
STATEMENT BY APPLICANT(S)

Atty Docket No. : 11809/27
 Serial No. : 10/735,695
 Inventors : Glen Carey, et al.
 Filed : 16 December 2003
 Group Art Unit : 2812
 Examiner :

U.S. PATENT DOCUMENTS

Examiner Initial	Patent Number	Patent Date	Name	Class/ Subclass	Filing Date
	2002-0054618	05/09/02	JIANG, et al.	372/50	
	6,327,293	12/04/01	SALOKATVE et al.	372/96	
	2002/0080836	06/27/02	HWANG	372/45	
	2002/0177246	11/28/02	HANG, et al.	438/22	
	3,649,382	03/24/72	HAWRYLO	148/171	

FOREIGN PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Country	Class/ Subclass	Translation Yes <input checked="" type="checkbox"/> No <input type="checkbox"/>
	100 22 879	12/14/00	EPO		X

OTHER DOCUMENTS

(Including Author, Title, Date, Pertinent Pages, Etc.)

Examiner Initial

1. B. Corbett, et al.: Low-stress hybridization of emitters, detectors and driver circuitry on a silicon motherboard for optoelectronic interconnect architecture, MATERIALS SCIENCE IN SEMICONDUCTOR PROCESSING, Vol. 3, No. 5-6, 2000, pp. 449-453
2. R. Pu, et al.: Comparison of techniques for bonding VCSELs directly to Ics, JOURNAL OF OPTICS A: PURE AND APPLIED OPTICS, Vol. 1, No. 2, March 1999, pp. 324-329
3. Bernd Jenichen, et al.: Crystal defects in vertical cavity epitaxial structures on GaAs investigated by X-ray methods, MATERIALS SCIENCE AND ENGINEERING B, ELSEVIER SEQUOIA, LAUSANNE, CH, Vol. 28, No. 1/3, 1 December 1994, pp. 520-522

EXAMINER

DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.